# Octal 3-State Noninverting D Flip-Flop with LSTTL-Compatible Inputs

### High–Performance Silicon–Gate CMOS

The MC74HCT374A may be used as a level converter for interfacing TTL or NMOS outputs to High–Speed CMOS inputs.

The HCT374A is identical in pinout to the LS374.

Data meeting the setup and hold time is clocked to the outputs with the rising edge of Clock. The Output Enable does not affect the state of the flip–flops, but when Output Enable is high, the outputs are forced to the high–impedance state. Thus, data may be stored even when the outputs are not enabled.

The HCT374A is identical in function to the HCT574A, which has the input pins on the opposite side of the package from the output pins. This device is similar in function to the HCT534A, which has inverting outputs.

### Features

- Output Drive Capability: 15 LSTTL Loads
- TTL/NMOS-Compatible Input Levels
- Outputs Directly Interface to CMOS, NMOS, and TTL
- Operating Voltage Range: 4.5 to 5.5 V
- Low Input Current: 1.0 μA
- In Compliance With the JEDEC Standard No. 7.0 A Requirements
- Chip Complexity: 276 FETs or 69 Equivalent Gates
- Improvements over HCT374
  - Improved Propagation Delays
  - ✤ 50% Lower Quiescent Power
  - Improved Input Noise and Latchup Immunity
- These Devices are Pb-Free and are RoHS Compliant



### LOGIC DIAGRAM



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### **PIN ASSIGNMENT**

OUTPUT ENABLE	ſ	1•	20	þ	V <sub>CC</sub>
Q0		2	19	þ	Q7
D0		3	18	þ	D7
D1		4	17	þ	D6
Q1		5	16	þ	Q6
Q2		6	15	þ	Q5
D2		7	14	þ	D5
D3		8	13	þ	D4
Q3		9	12	þ	Q4
GND I		10	11	þ	CLOCK

### MARKING DIAGRAMS



#### **FUNCTION TABLE** Inputs Output Output Enable D Q Clock н Н L L L L L L,H, Х No Change н Х Х Ζ X = don't care

Z = high impedance

### **ORDERING INFORMATION**

See detailed ordering and shipping information on page 5 of this data sheet.

Design Criteria	Value	Units
Internal Gate Count*	69	ea.
Internal Gate Propagation Delay	1.5	ns
Internal Gate Power Dissipation	5.0	μW
Speed Power Product	.0075	рJ

\*Equivalent to a two-input NAND gate.

### MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	-0.5 to +7.0	V
V <sub>in</sub>	DC Input Voltage (Referenced to GND)	-0.5 to V <sub>CC</sub> + 0.5	V
Vout	DC Output Voltage (Referenced to GND)	-0.5 to V <sub>CC</sub> + 0.5	V
l <sub>in</sub>	DC Input Current, per Pin	±20	mA
l <sub>out</sub>	DC Output Current, per Pin	±35	mA
ICC	DC Supply Current, V <sub>CC</sub> and GND Pins	±75	mA
P <sub>D</sub>	Power Dissipation in Still Air, SOIC Package† TSSOP Package†	500 450	mW
T <sub>stg</sub>	Storage Temperature	-65 to +150	°C
TL	Lead Temperature, 1 mm from Case for 10 Seconds (SOIC or TSSOP Package)	260	°C

This device contains protection circuitry to guard against damage due to high static voltages or electric fields. However, precautions must be taken to avoid applications of any voltage higher than maximum rated voltages to this high–impedance circuit. For proper operation,  $V_{in}$  and  $V_{out}$  should be constrained to the range GND  $\leq (V_{in} \text{ or } V_{out}) \leq V_{CC}$ . Unused inputs must always be tied to an appropriate logic voltage level (e.g., either GND or  $V_{CC}$ ). Unused outputs must be left open.

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

†Derating: SOIC Package: -7 mW/°C from 65° to 125°C

TSSOP Package: -6.1 mW/°C from 65° to 125°C

### **RECOMMENDED OPERATING CONDITIONS**

Symbol	Parameter	Min	Max	Unit
V <sub>CC</sub>	DC Supply Voltage (Referenced to GND)	4.5	5.5	V
V <sub>in</sub> , V <sub>out</sub>	DC Input Voltage, Output Voltage (Referenced to GND)	0	V <sub>CC</sub>	V
T <sub>A</sub>	Operating Temperature, All Package Types	-55	+125	°C
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time (Figure 1)	0	500	ns

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

				Guaranteed Limit			
Symbol	Parameter	Test Conditions	V <sub>CC</sub> V	–55 to 25°C	≤ <b>85</b> °C	: ≤ 125°C	Unit
V <sub>IH</sub>	Minimum High-Level Input Voltage	$ \begin{aligned} V_{out} &= 0.1 \text{ V or } V_{CC} - 0.1 \text{ V} \\  I_{out}  &\leq 20 \ \mu\text{A} \end{aligned} $	4.5 5.5	2.0 2.0	2.0 2.0	2.0 2.0	V
V <sub>IL</sub>	Maximum Low-Level Input Voltage	$ \begin{aligned} V_{out} &= 0.1 \text{ V or } V_{CC} - 0.1 \text{ V} \\  I_{out}  &\leq 20 \ \mu\text{A} \end{aligned} $	4.5 5.5	0.8 0.8	0.8 0.8	0.8 0.8	V
V <sub>OH</sub>	Minimum High-Level Output Voltage	$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 20 \ \mu A$	4.5 5.5	4.4 5.4	4.4 5.4	4.4 5.4	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 6.0 \text{ mA}$	4.5	3.98	3.84	3.7	
V <sub>OL</sub>	Maximum Low-Level Output Voltage	$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 20 \ \mu A$	4.5 5.5	0.1 0.1	0.1 0.1	0.1 0.1	V
		$V_{in} = V_{IH} \text{ or } V_{IL}$ $ I_{out}  \le 6.0 \text{ mA}$	4.5	0.26	0.33	0.4	
l <sub>in</sub>	Maximum Input Leakage Current	V <sub>in</sub> = V <sub>CC</sub> or GND	5.5	±0.1	±1.0	±1.0	μΑ
I <sub>OZ</sub>	Maximum Three–State Leakage Current	Output in High–Impedance State $V_{in} = V_{IL} \text{ or } V_{IH}$ $V_{out} = V_{CC} \text{ or GND}$	5.5	±0.5	±5.0	±10	μΑ
Icc	Maximum Quiescent Supply Current (per Package)	$V_{in} = V_{CC} \text{ or GND}$ $I_{out} = 0 \ \mu A$	5.5	4.0	40	160	μΑ
$\Delta I_{CC}$	Additional Quiescent Supply Current	$V_{in} = 2.4 \text{ V}$ , Any One Input		≥ <b>-55°</b> 0	25	°C to 125°C	
		$V_{in} = V_{CC}$ or GND, Other Inputs $I_{out} = 0 \mu A$	5.5	2.9		2.4	mA

#### DC ELECTRICAL CHARACTERISTICS (Voltages Referenced to GND)

1. Total Supply Current =  $I_{CC} + \Sigma \Delta I_{CC}$ .

## AC ELECTRICAL CHARACTERISTICS (V\_{CC} = 5.0 V $\pm 10\%, \ C_L = 50 \ \text{pF}, \ \text{Input} \ t_{\text{f}} = t_{\text{f}} = 6.0 \ \text{ns})$

		Gua	ranteed Limi	it	
Symbol	Parameter	–55 to 25°C	≤ 85°C	≤ 125°C	Unit
f <sub>max</sub>	Maximum Clock Frequency (50% Duty Cycle) (Figures 1 and 4)	30	24	20	MHz
t <sub>PLH</sub> , t <sub>PHL</sub>	Maximum Propagation Delay, Clock to Q (Figures 1 and 4)	31	39	47	ns
t <sub>PLZ</sub> , t <sub>PHZ</sub>	Maximum Propagation Delay, Output Enable to Q (Figures 2 and 5)	30	38	45	ns
t <sub>PZL</sub> , t <sub>PZH</sub>	Maximum Propagation Delay, Output Enable to Q (Figures 2 and 5)	30	38	45	ns
t <sub>TLH</sub> , t <sub>THL</sub>	Maximum Output Transition Time, Any Output (Figures 1 and 4)	12	15	18	ns
C <sub>in</sub>	Maximum Input Capacitance	10	10	10	pF
C <sub>out</sub>	Maximum Three–State Output Capacitance (Output in High–Impedance State)	15	15	15	pF

		Typical @ 25°C, V <sub>CC</sub> = 5.0 V	
C <sub>PD</sub>	Power Dissipation Capacitance (Per Flip–Flop)*	65	pF

\* Used to determine the no–load dynamic power consumption:  $P_D = C_{PD} V_{CC}^2 f + I_{CC} V_{CC}$ .

### **TIMING REQUIREMENTS** (V<sub>CC</sub> = 5.0 V $\pm$ 10%, Input t<sub>r</sub> = t<sub>f</sub> = 6.0 ns)

		Guaranteed Limit			
Symbol	Parameter	–55 to 25°C	≤ 85°C	≤ 125°C	Unit
t <sub>su</sub>	Minimum Setup Time, Data to Clock (Figure 3)	12	15	18	ns
t <sub>h</sub>	Minimum Hold Time, Clock to Data (Figure 3)	5.0	5.0	5.0	ns
t <sub>w</sub>	Minimum Pulse Width, Clock (Figure 1)	12	15	18	ns
t <sub>r</sub> , t <sub>f</sub>	Maximum Input Rise and Fall Times (Figure 1)	500	500	500	ns

### SWITCHING WAVEFORMS



Figure 1.







Figure 3.

### **TEST CIRCUITS**



Figure 4.

Figure 5.

### EXPANDED LOGIC DIAGRAM



### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
MC74HCT374ADWG	SOIC-20 (Pb-Free)	38 Units / Rail
MC74HCT374ADWR2G	SOIC-20 (Pb-Free)	1000 Units / Reel
MC74HCT374ADTR2G	TSSOP–20 (Pb–Free)	2500 Units / Reel

+For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

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